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1. Special Circuits Development

Area 1—Work Involved: directing the efforts of an expanding analog circuits development group. This group is presently engaged in the application of new analog-digital techniques to the measurement and control of industrial processes. This is a senior position with a growing activity—for a man who has already made an outstanding contribution to his field.

Education: B.S. or M.S. in Electrical Engineering, with especial concentration in circuit analysis.

Experience: 5 to 10 years in designing analog circuits, especially as applied to process control or aerospace instruments.

Area 2—Work Involved: participating in the activities of an analog circuits development group. There are several senior positions in this expanding group open to engineers with outstanding contributions to their credit in this field.

Education: B.S. or M.S. in Electrical Engineering, showing a major interest in circuit analysis.

Experience: 2 to 5 years of designing low-level instrument amplifiers, for either process control or aerospace applications. Must be capable of theoretical circuit analysis and have some knowledge of component evaluation.

2. Mechanical Development

Area 3—Work Involved: directing the efforts of an expanding mechanical development group at present engaged in analyzing new measurement and control techniques for industrial processes. For this senior position of increasing responsibility, we are looking for a man who has made an outstanding contribution in the field. Computer systems experience is not necessarily a requirement.

Education: an advanced degree in Mechanical Engineering or related field.

Experience: 5 to 10 years in automatic control instrumentation and mechanism design. Knowledge of materials suitable for use in industrial processes is necessary. A minimum of 2 years' managerial experience in a similar activity is desirable.

Area 4—Work Involved: participating in the activities of the above mechanical development group. There are several senior positions in this growing organization open to mechanical engineers who have made outstanding contributions to the field of measurement and control techniques for industrial processes, though computer systems experience is not necessarily required.

Education: B.S. or M.S. in Mechanical Engineering or a related field.

Experience: 2 to 5 years in the designing of automatic control instrumentation. Some knowledge of materials suitable for use in industrial processes is necessary.

3. Engineer-Planners

Area 5—Work Involved: participating in the planning activities of a growing area. This is a challenging opportunity to apply an industrial instrumentation background to the solution of problems as they relate to components of industrial process control systems.

Education: B.S. in Electrical, Mechanical, or General Engineering.

Experience: 5 to 10 years' experience is required in planning engineering design as related to the instrumentation needs of various industries, such as chemical, petroleum, steel, textile, or paper.

Please write, outlining your background, to: R. G. Cowie, Dept. 571M, IBM Corp., Monterey and Cottle Roads, San Jose 14, Calif.